classify(1) classify(1)

NAME

classify - secondary classification program

SYNOPSIS

classify [dirname] probname

DESCRIPTION

classify adds probname to the database file CLASSF.DB.

classify Options

You can start classify with the following options:

dirname

probname is searched for in dirname. If dirname is not specified, MASTSIF is searched.

ENVIRONMENT

SIFDECODE

Parent directory for SIFDecode.

MASTSIF

A pointer to the directory containing the CUTEst/SIFDecode problems collection.

AUTHORS

I. Bongartz, A.R. Conn, N.I.M. Gould, D. Orban and Ph.L. Toint

SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads, N.I.M. Gould, D. Orban and Ph.L. Toint,

Technical Report, Rutherford Appleton Laboratory, 2013.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited N.I.M. Gould, D. Orban and Ph.L. Toint, ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment, I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint, ACM TOMS, 21:1, pp.123-160, 1995.

classall(1), select(1).

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